SPECIFICATIONS

General

Maximum Analog Test Points	640 points
Windows Compatible PC or Laptop with USB Ports	
Operation System	Microsoft® Windows 7
Power Requirement	100 - 240 V, Single phase, 50/60 Hz, 300 VA
Fixture Type	Press or manual

Analog Hardware

Measurement Switching Matrix 6-wire measurement

Programmable Frequency	100 Hz, 1 kHz, 10 kHz, 100 kHz
Programmable DC Voltage Source	±10 V maximum, resolution: 10 mV
Programmable DC Current Source	100 mA maximum
Programmable AC Voltage Source	10 Vpp maximum, resolution: 10 mV

Component Measurement Capability

Resistance	40 mohm – 40 Mohm
Capacitance	10 pF – 40 mF
Inductance	10 μH – 60 H

Analog Measurement

AC Voltmeter	0 – 100 Vp
DC Voltmeter	0 – ±100 V, resolution: 2.5 mV – 50 mV
DC Ampmeter	1 μA – 100 mA, resolution: 30 nA – 30 μA

Optional Hardware

Dual-Stage Press Unit or Inline Handler

TestJet Technology	Vectorless open circuit detection
Programmable High Voltage DC Source	Up to 100 V/100 mA
Sine Wave Generator Frequency range	1 – 100 kHz, resolution: 1 Hz
Frequency Measurement	Up to 200 MHz

Serial Test Module (STM)

Two channels for serial Testing up to 1MHz with 16 Channels of General Purpose Digital I/O	
Boundary Scan Nail connection Test(PISO/SIPO), Toggle Scan, SPI/I^2C and UART	
Programmable Voltage Level	Vih: 0.8 V – 4.6 V at Io=20 mA; Voh: 0.1 V – 4.9 V

Data Acquisition

Two Channels, 16 bits 10 MSPS flexible arbitrary / DDS waveform generator

Four Channels, 16 bits 3.8 MSPS waveform digitizer

One Channel frequency generator

Audio Analyzer

24-bit Audio analyzer with SNR, THD and THD+N analysis

Digital Test Module

Four Programmable DUT Power Supply	1 – 20 V, 0.6 – 2 A, 12 Watt, current measurement 100 μA – 2 A
Two Fixed ,12V and -12V Power	0.3 A, current measurement 10 mA – 300 mA
Sixteen channels General Purpose Digital I/O	

Dimensions/Weight

Dimensions	(W) 334 x (D) 260 x (H) 182 mm (does not include notebook and accessories)
Weight	8 – 11 kg (does not include notebook or accessories; final weight determined by system selected)

Powerful Software Environment

Auto debug for all passive tests (shorts/opens, R/L/C components, clamping diodes, and TestJet)

Built-in system diagnostics

Test Coverage and C_{pk} reporting are standard

Board View will visually highlight failures to device/pin/trace level

Board Revision software (single program for multiple board versions)

Program Modification Report (Reports any changes to program after release)

Shop floor system support

Test Research, Inc.

Headquarters
7F., No.45, Dexing West Rd.,
Shilin Dist., Taipei City
11158, Taiwan
TEL: +886-2-2832-8918
FAX: +886-2-2831-0567
E-Mail: sales@tri.com.tw
http://www.tri.com.tw

Linkou, Taiwan
No.256, Huaya 2nd Rd.,
Guishan Shiang, Taoyuan
County 33383, Taiwan
TEL: +886-2-2832-8918
FAX: +886-3-328-6579

Hsinchu, Taiwan
7F., No.47, Guangming 6th
Rd., Zhubei City, Hsinchu
County 30268, Taiwan
TEL: +886-2-2832-8918
FAX: +886-3-553-9786

Shenzhen, China
5F.3, Guangxia Rd., Shang-mei-lin
Area, Fu-Tian District, Shenzhen,
Guangdong, 518049, China
TEL: +86-755-83112668
FAX: +86-755-83108177
E-mail: shenzhen@cn.tri.com.tw

Suzhou, China
63 Huoju Road, Suzhou New
District, 215009, China
TEL: +86-512-68250001
FAX: +86-512-68096639
E-mail: suzhou@cn.tri.com.tw

Shanghai, China
W. 6F., Building18, 481 Guiping
Road, Shanghai, 200233, China
TEL: +86-21-54270101
FAX: +86-21-64957923
E-mail: shanghai@cn.tri.com.tw

USA
1923 Hartog Drive
San Jose, CA 95131 U.S.A
TEL: +1-408-567-9898
FAX: +1-408-567-9288
E-mail: triusa@tri.com.tw

Europe
O'Brien Strasse 14
91126 Schwabach
Germany
TEL: +49-9122-631-2127
FAX: +49-9122-631-2147
E-mail: trieurope@tri.com.tw

Japan
2-9-9 Midori, Sumida-ku,
Tokyo, 130-0021 Japan
TEL: +81-3-6273-0518
FAX: +81-3-6273-0519
E-mail: trijp@tri.com.tw

Korea
No.207 Daewoo-Technopia,
768-1 Wonsi-Dong, Danwon-Gu,
Ansan City, Gyeonggi-Do, Korea
TEL: +82-31-470-8858
FAX: +82-31-470-8859
E-mail: trikr@tri.com.tw

Malaysia
C11-1, Ground Floor, Lorong
Bayan Indah 3 Bay Avenue,
11900 Bayan Lepas Penang,
Malaysia
TEL: +604-6461171
E-mail: trimy@tri.com.tw

C-5001T SII TINY-EN-1308

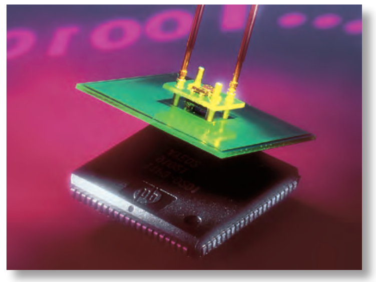
TRI
innovation

TR5001T SII TINY

SERIES

IN-CIRCUIT TESTER

TR5001T SII TINY FEATURES



TestJet Technology

Manufacturing Defect Analyzer

RLC Measurement

- 6-Wire Measurement
- Auto-Guarding Feature
- AC Phase Measurement
- High-Speed Test

TestJet Technology

Detects open connections on ICs, connectors and other SMT devices.

Capacitor Polarity Test

- Leakage Current Measurement
- TestJet Detection

Transistor/Diode Measurement

- Diode
- Zener Diode
- Transistor: PNP, NPN
- FET/SCR/TRIAC
- Photo Coupler

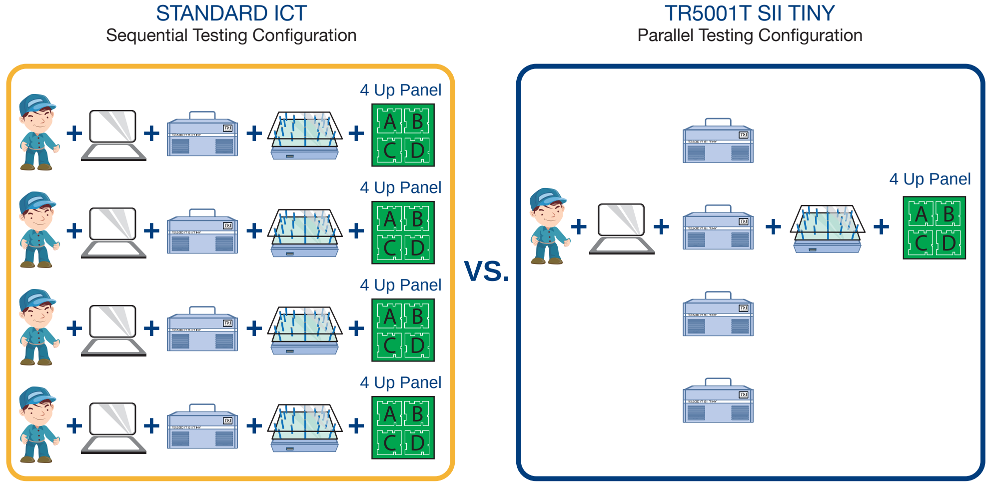
New Features

- *World's Most Compact, Lightweight and Powerful ICT*
- *Parallel Testing Configuration*
- *Serial Device Programming*
- *Boundary Scan Test*
- *Audio Analyzer*
- *USB Connection*

Up to 75% operator, PC and fixture cost reduction in parallel configuration!

Parallel Testing Configuration

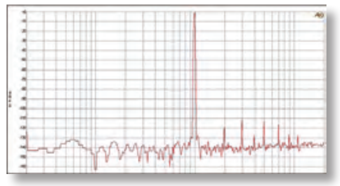
Parallel testing configuration offers up to 75% reduction in operator, PC and fixture costs for multi panel boards.



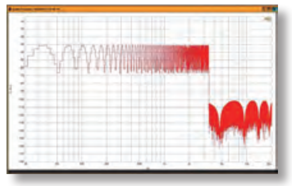
Audio Analyzer and Data Acquisition

Enables audio signal distortion analysis and speaker quality testing using single and multi-tone analysis.

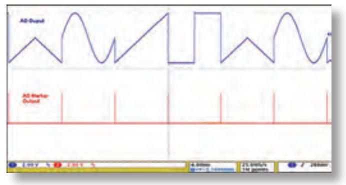
Arbitrary waveform generator enables testing of systems with complex triggering preconditions and high speed data acquisition.



Single Tone Analysis



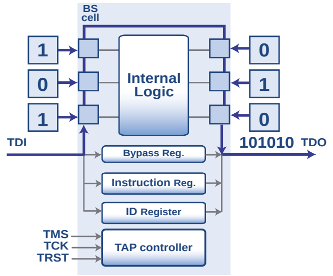
Multi Tone Analysis



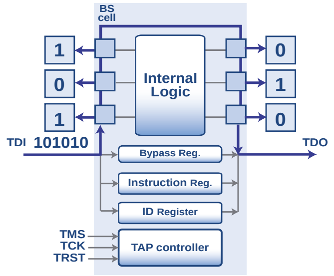
Arbitrary Waveform Generator

Boundary Scan Test

Limited test access technology for testing component dense PCBAs with BSCAN enabled devices.



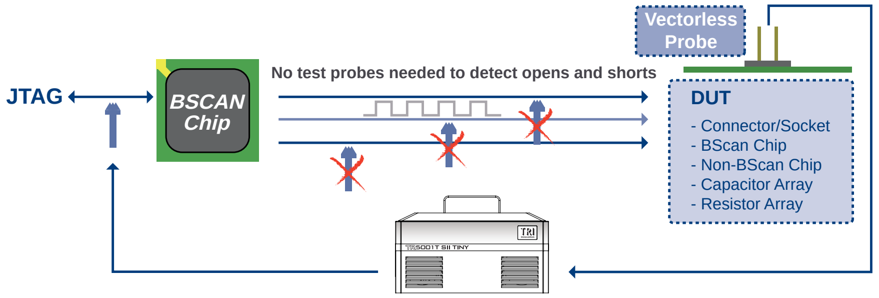
Parallel in Serial out



Serial in Parallel out

TRI ToggleScan^{TM} Test

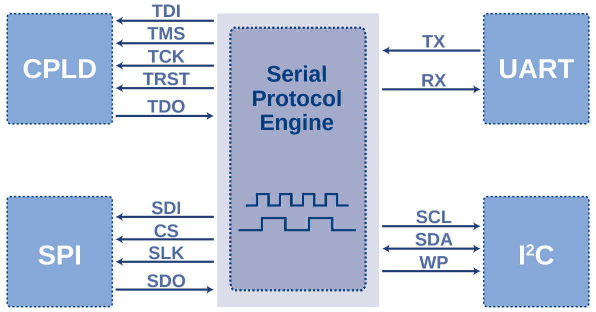
Patented no test access technology for maximum coverage of component dense PCBAs using standard TestJet technology. Detects opens and shorts on a wide range of devices.



High Speed Serial Device Programing & Testing

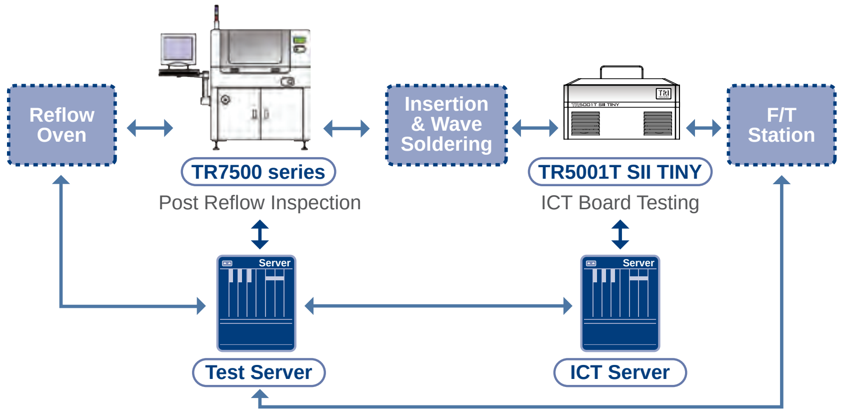
Built-in application for programming and testing of supported onboard serial devices, including writing MAC addresses, firmware, and device IDs.

- SPI
- I²C
- CPLD
- UART

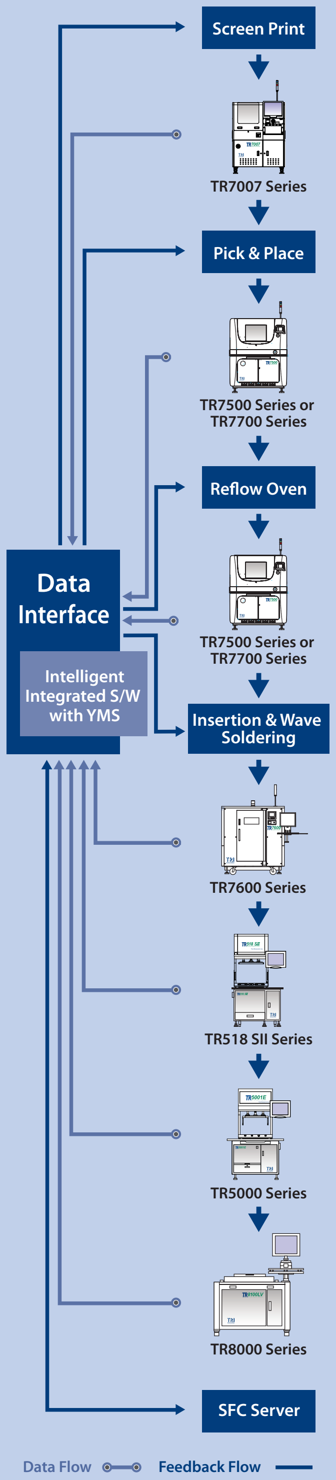


Shop Floor System Support

Integrated data exchange solution that allows performance analysis of production line data for quality assurance and engineering analysis.



Yield Management System*



- Testers enable process capability control
- Real-time defect information integration & analysis
- Defect knowledge management

* Optional